The 4th International Workshop on Metrology for X-ray Optics, Mirror Design, and Fabrication will be held in Barcelona, Spain, as a satellite workshop of the Synchrotron Radiation and Instrumentation-SRI conference 2012. The workshop merges the fifth workshop on Active X-ray and XUV optics (ACTOP 2012) and the third International Workshop on Metrology for X-ray and XUV Optics. It will provide a forum for presentation and discussion on the latest developments in X-ray optics, with particular regard to improvements in metrology and results on deformable mirrors.

Topics

• Fabrication and finishing technology for X-ray mirrors
• Metrology challenges for X-ray mirrors
• Active and adaptive optics for X-ray applications
• X-ray beam shaping, wave front optimization and coherence preservation
• In-situ metrology and wave front measurements
• Optics for ultra-short/ultra-intense pulses
• Multilayer optics characterization and metrology
• Beamline performance and scientific results obtained by using novel optical schemes
• Specifications for optics at new storage ring and free-electron laser sources
• Simulation and data analysis
• Theoretical framework for describing source coherence, and the propagation of mutual coherence, along with analytical- and numerical- modeling.
• Measurements of spatial and temporal coherence

International advisory committee
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